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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10001483	FILING DATE 11/01/2001	CLASS 438	SUBCLASS	GAU 2812	EXAMINER
**APPLICANTS: Rotondaro Antonio;					
**CONTINUING DATA VERIFIED: THIS APPLN CLAIMS BENEFIT OF 60/247,408 11/10/2000					
** FOREIGN APPLICATIONS VERIFIED:					
PG-PUB <input type="checkbox"/>		DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>	
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials				ATTORNEY DOCKET NO TI-31133	
TITLE : Method to improve the uniformity and reduce the surface roughness of the silicon dielectric interface					
U.S DEPT. OF COMMERCE / PAT & TM-PTO-436L (Rev. 12-94)					

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	
		Print Claim for O.G.	
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drawg.	Figs. Drawg.
		Print Fig.	
		Application Examiner	
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	
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